Search Notes		

Application/Co	ontrol No.	Applicant(s)/Patent Reexamination	under
10/710,551		OKUIE ET AL.	
Examiner		Art Unit	
Huan H. Tran		2861	

SEARCHED			
Class	Subclass	Date	Examiner
347	214,177 178	3/22/2006	ннт
400	207,208.1	3/22/2006	ннт
1			
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
347/214, 177,178; 400/207,208,208.1 (text search only (USPAT;USPG_PUB;JPO;EPO;DER WENT;IBM_TDB)-see search history printout	3/22/2006	ннт
B41J032/00;017/22;017/24_text search only_see search history printout	3/22/2006	ннт